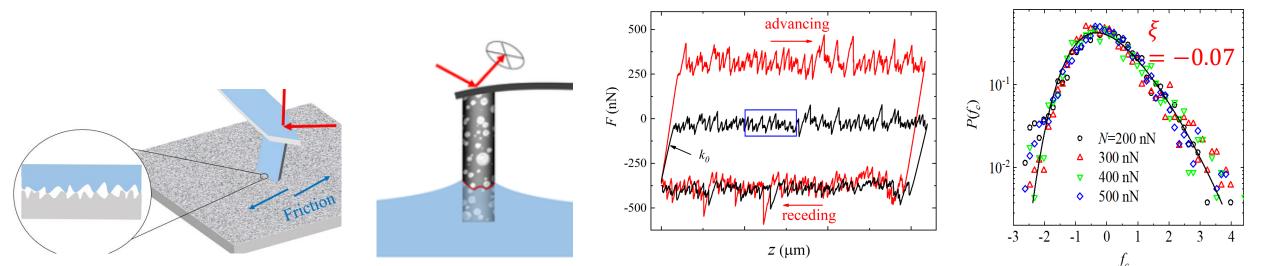
Stick-slip dynamics, Extreme value statistics & avalanches in moving contact lines and solid friction

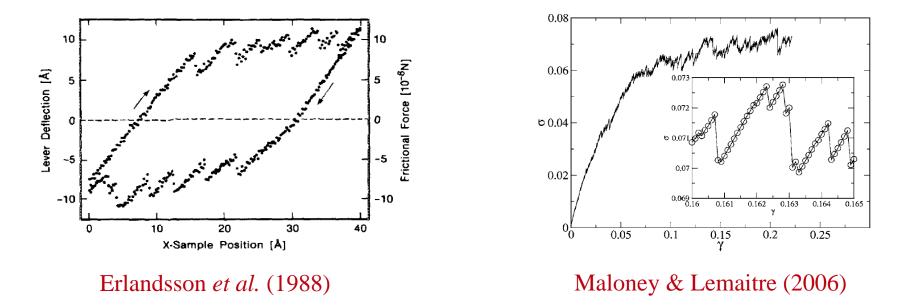
- Caishan Yan, Hsuan-Yi Chen, Pik-Yin Lai (黎璧賢), Penger Tong Dept. of Physics & Center for Complex Systems, National Central Univ., Taiwan Physics, Division, National Center for Theoretical Sciences, Taipei, Taiwan Email: pylai@phy.ncu.edu.tw
- Introduction
- Stick-slip dynamics of a mesoscale moving contact line
- Stick-slip motion of dry friction at mesoscale
- Modified Prandtl and Tomlinson (PT) model
- "Statistical laws of stick-slip friction at mesoscale", Nature Comm. **14**:6221 (2023).
- "Avalanches and extreme value statistics of a mesoscale moving contact line, PRL **132**, 084003 (2024) (Editor's suggestion)



DDAP13 Kyoto, July 2024

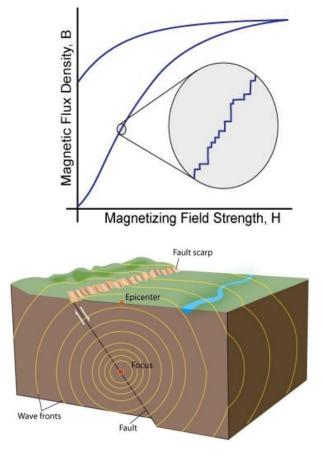
Stick-slip and avalanche dynamics

• Stick-slip is a class of phenomena characterized by intermittent jerky movement in out-of-equilibrium disordered systems, as a yield response to a smoothly-varying external force.



• It is observed in nature and many engineering applications that span a wide range of scales, from the nanoscale contacts and fractures in nano- and micro-machines/devices to the geophysical scale of snow avalanches, landslides and earthquakes.

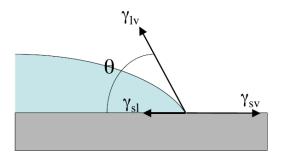
- Rapture of single molecules (zero-dimension)
- Pinning and depinning of a three-phase contact line and vortex lines in type-II superconductors (one-dimension)
- Friction between two solid surfaces and dynamics of ferromagnetic domain walls (two-dimension)
- > Plasticity of amorphous solids under a simple shear (three-dimension)
- A common feature of stick-slip events is their broad range of slip lengths, manifest as power-law distributions of many orders of magnitude. The fact that very different systems behave in a similar manner has prompted extensive investigations for a common mechanism underpinning these phenomena.
- There are a number models and proposals aimed at explaining the power-law distributions, but many of them have not been confirmed by experiment. Theory and experiment do not converge, because the out-of-equilibrium systems involved are often disordered, and disorder has many different forms.



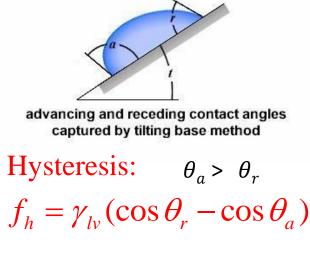


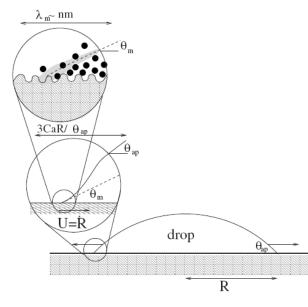
pinning-depinning of a three-phase contact line

For an idealized surface (atomically smooth, chemically homogenous & infinitely hard) at equilibrium:



Young's equation: $\gamma_{lv} \cos \theta = \gamma_{sv} - \gamma_{sl}$

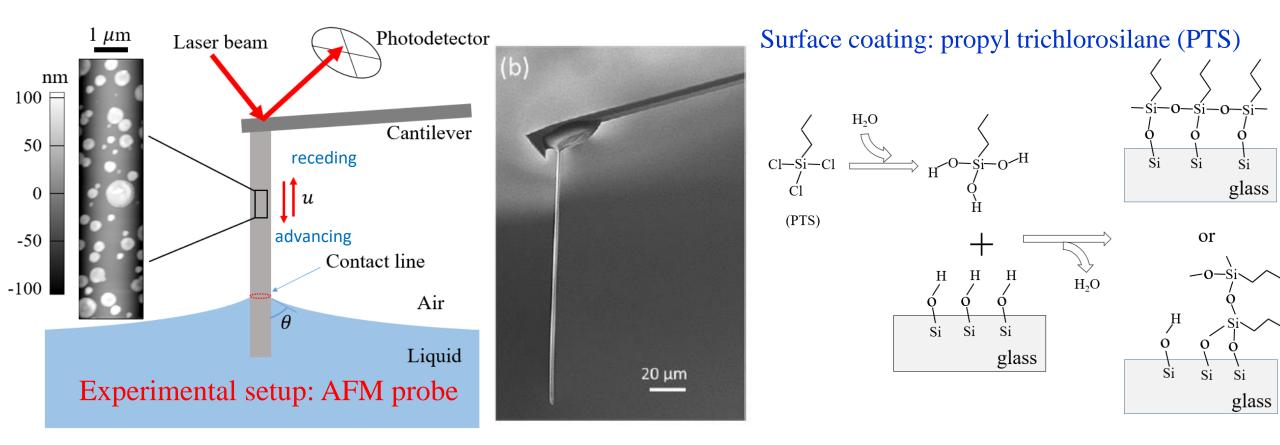




- Contact angle hysteresis (or capillary force hysteresis) is caused by the pinning of the contact line by physical roughness or chemical heterogeneity on the solid surface $(\delta x = (k_B T/\gamma)^{1/2} \approx 0.2$ nm).
- For mesoscale systems, one finds large amplitude fluctuations of the capillary force, in addition to its mean value change f_h .
- How contact angle hysteresis is determined by the underlying pinning force field?

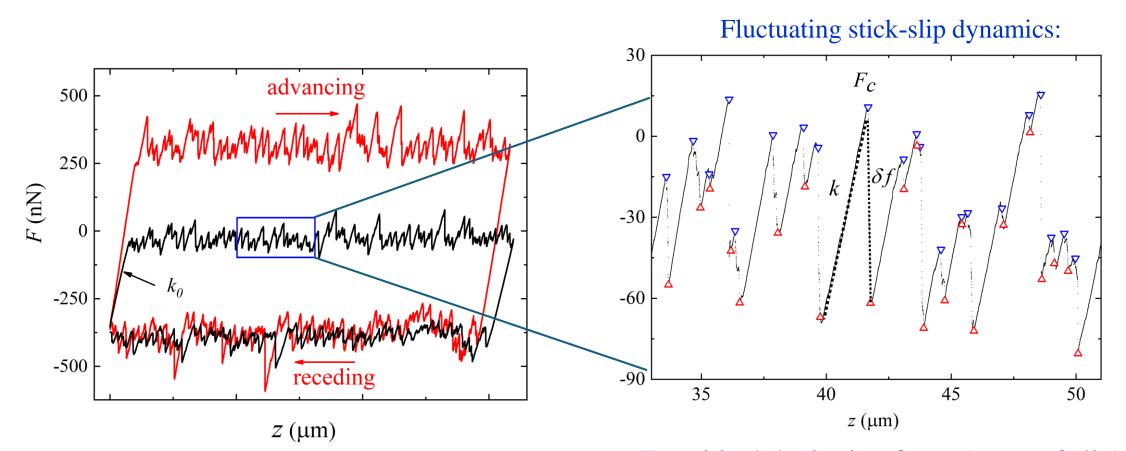
Stick-slip dynamics of a moving contact line at mesoscales:

small enough to resolve the slip events at the single slip resolution but is also large enough to allow the individual slips to have a broad range of slip sizes in a well-characterized defect landscape



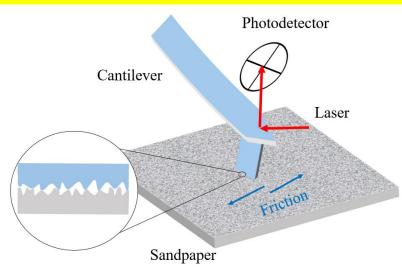
- Long glass fiber diameter $d: 0.4-4 \mu m$, at mesoscale to resolve single slip events
- fiber length L: $100-300 \,\mu\text{m}$
- Low-speed limit: $u \sim 0.62 \mu m / s$ (viscous drag is negligible)

Stick-slip dynamics of a moving contact line

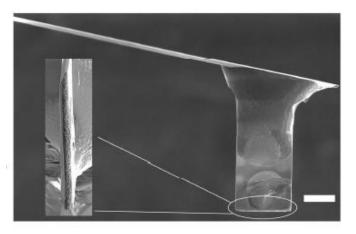


Capillary force hysteresis loop for water (red) and ethylene glycol (black) Static spring constant of the liquid interface, $k_0 \sim \gamma$ F_c : critical depinning force (onset of slip) δf : force release during the slip k: dynamics spring constant of interface (linear force accumulation) 6

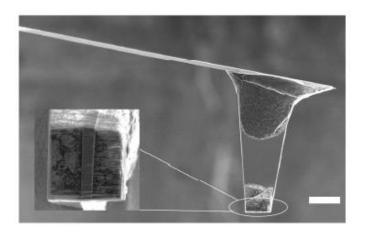
Stick-slip dynamics of friction between 2 solid surfaces



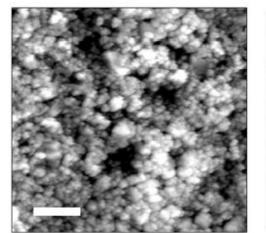
Lateral hanging-beam AFM



Quasi-1D scanning probe with an end contact area of $34 \times 3 \ \mu m^2$ (UV glue)



2D scanning probe with an end contact area of $12 \times 12 \ \mu m^2$ (UV glue).

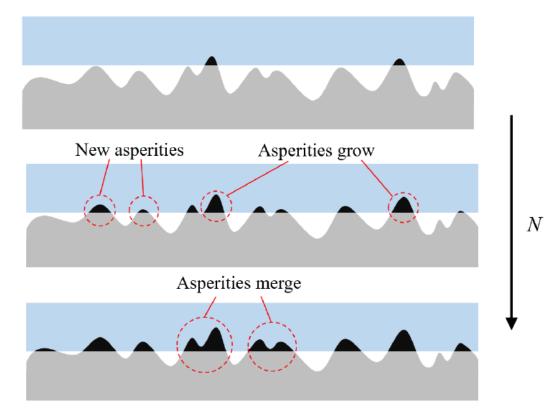


- 200 nm - 100 - 0 - 100

-200

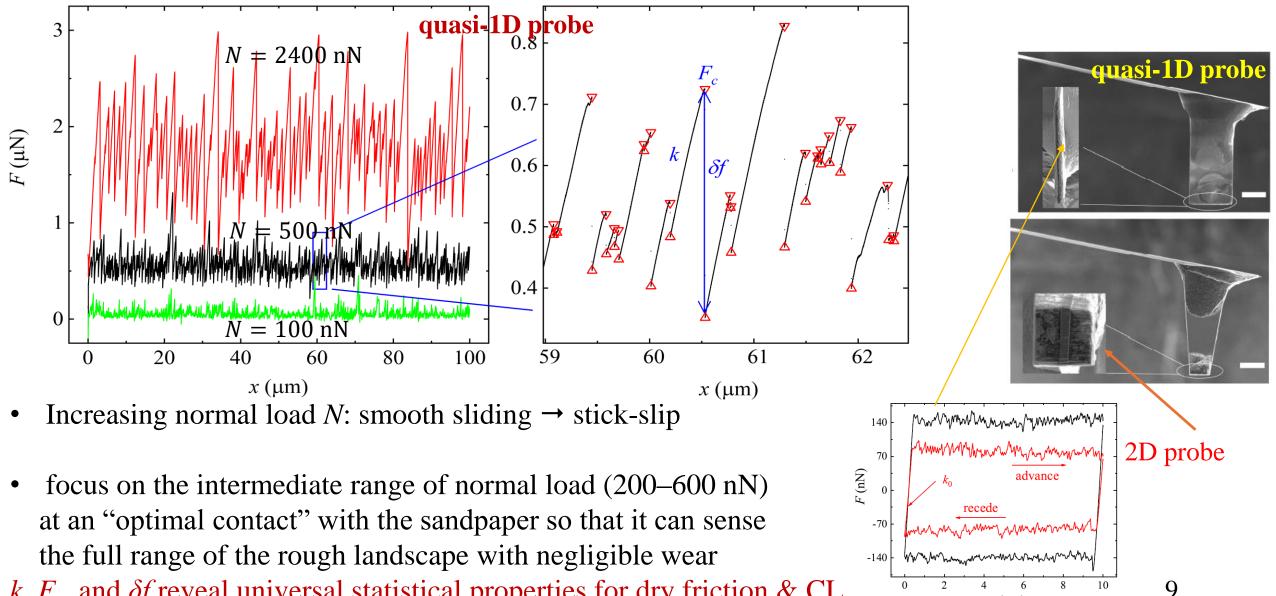
Ultra-fine sandpaper (silicon carbide) surface with an average grain size 0.1 um

Evolution of contact geometry with increasing normal load N



- In the low-load regime, the asperities (or microcontacts) at the interface are dilute, and their number increases with the normal load *N*.
- In the high-load regime, coalescence between nearby asperities occurs.
- In the intermediate range of N (200–600 nN), an "optimal contact" between the scanning probe and sandpaper is achieved, with the number of the asperities is kept at ~O(100) for a mesoscale scanning probe.

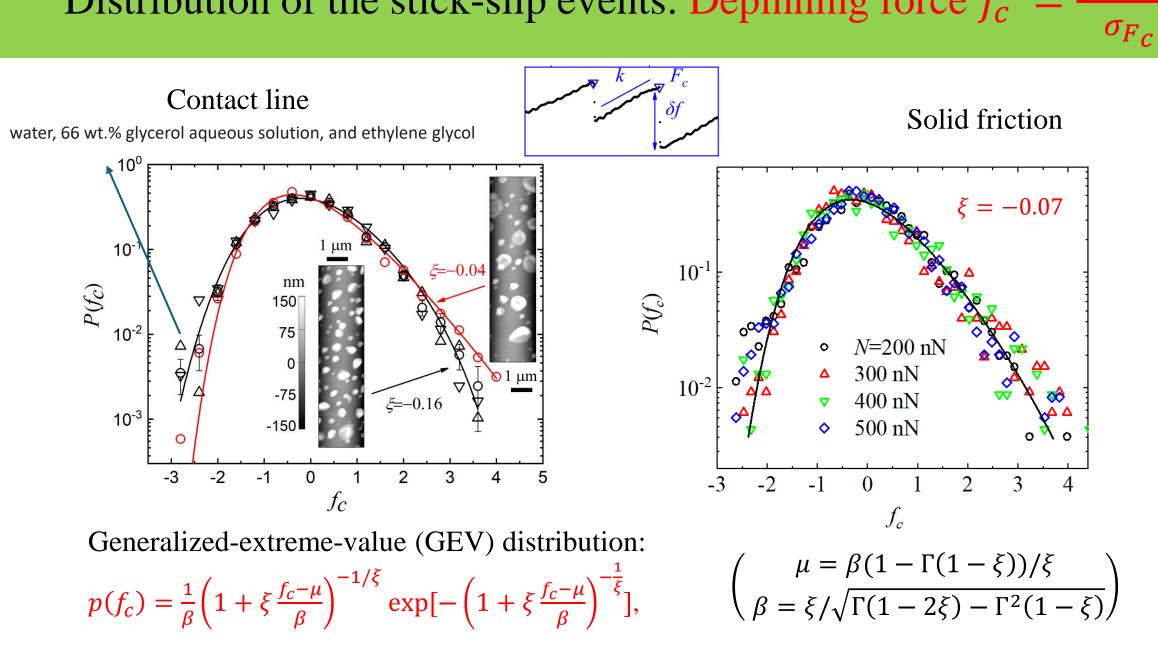
Stick-slip dynamics of friction between 2 solid surfaces



 $x (\mu m)$

k, F_c , and δf reveal universal statistical properties for dry friction & CL

Distribution of the stick-slip events: Depinning force $f_c = \frac{F_c - \langle F_c \rangle}{\sigma}$



Generalized Extreme Value (GEV) distribution

- GEV models the distribution of extreme values in a dataset. Commonly used in environmental science, economics, and engineering to analyze events such as extreme weather conditions or financial market crashes.
- Help to understand how likely the extreme(the highest or lowest) values are to occur.
- Examples: predicting the maximum wind speed in a particular location, estimating the size of the worst floods in a river, or analyzing the extreme values of stock market returns during a financial crisis.

Statistics or distribution of the maximum (or minimum) of *n* (a large number) samples drawn independently from an identical probability distribution.

Extreme-value Theorem: the random variable $x = max\{X_i\}_{i=1}^n$ follows one

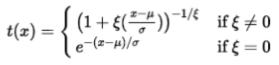
of the generalized extreme value (GEV) distributions

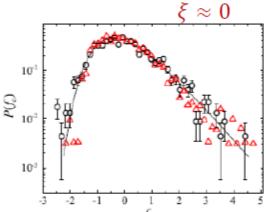
(the <u>Gumbel</u>, <u>Fréchet</u> and <u>Weibull</u> families also known as type I, II and III

extreme value distributions)

 $\operatorname{GEV}(\mu,\,\sigma,\,\xi) = \, \frac{1}{\sigma} \, t(x)^{\xi+1} e^{-t(x)},$

where





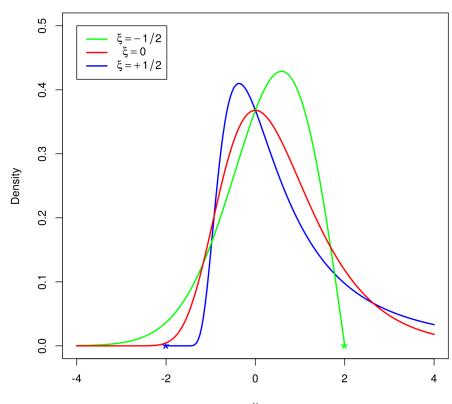
Extreme value Theorem: three types of GEV distributions

$$\operatorname{GEV}(\mu, \sigma, \xi) = \frac{1}{\sigma} t(x)^{\xi+1} e^{-t(x)},$$

where

$$t(x) = egin{cases} ig(1+\xi(rac{x-\mu}{\sigma})ig)^{-1/\xi} & ext{if } \xi
eq 0 \ e^{-(x-\mu)/\sigma} & ext{if } \xi = 0 \end{cases}$$

Generalized extreme value densities



All with μ = 0, σ = 1. Asterisks mark support-endpoints

• Gumbel or type I extreme value distribution (
$$\xi = 0$$
)

$$F(x;\mu,\sigma,0) = e^{-e^{-(x-\mu)/\sigma}} \text{ for } x \in \mathbb{R}.$$
Pdf: $p(x) = \frac{1}{\sigma} e^{-(z+e^{-z})} \text{ where } z = \frac{x-\mu}{\sigma}$
Cumulation distribution

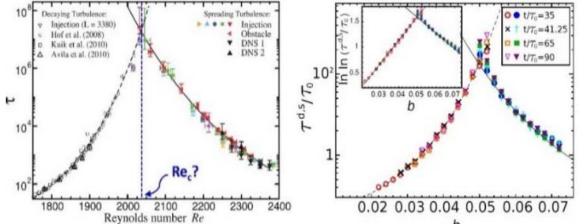
- Fréchet or type II extreme value distribution, if
$$\xi=lpha^{-1}>0$$
 and $y=1+\xi(x-\mu)/\sigma$

$$F(x;\mu,\sigma,\xi)=egin{cases} e^{-y^{-lpha}}&y>0\ 0&y\leq 0. \end{cases}$$

Reversed Weibull or type III extreme value distribution, if $\xi = -lpha^{-1} < 0$ and $y = -\left(1 + \xi(x-\mu)/\sigma\right)$

$$F(x;\mu,\sigma,\xi)=egin{cases} e^{-(-y)^lpha}&y<0\ 1&y\geq 0 \end{cases}$$

Characteristic time scales near the laminar-turbulent transition in the pipe flow



Avila et. al Science 333, 192 (2011) HY Shih et. al, Nat. Phys. **12**, 245,(2018)

Super-exponential in τ is related to Gumbel distribution: Active state persists until the **most** long-lived percolating strand decays

Characteristic time scales near the laminar-turbulent transition in the pipe flow (left) and the scaling near predator extinction in the predator-prey model (right). The mean decay and splitting times of the turbulent density and the prey density scale with Reynolds number

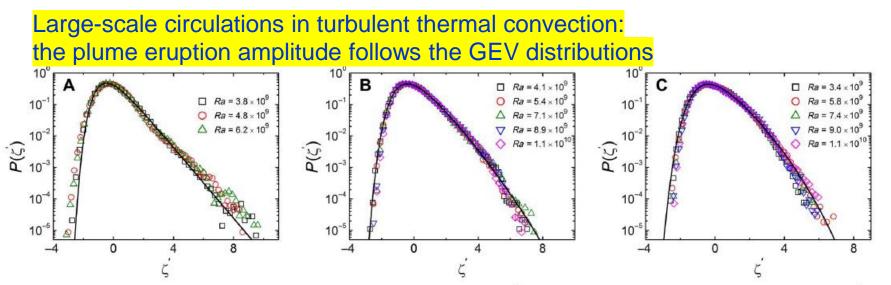
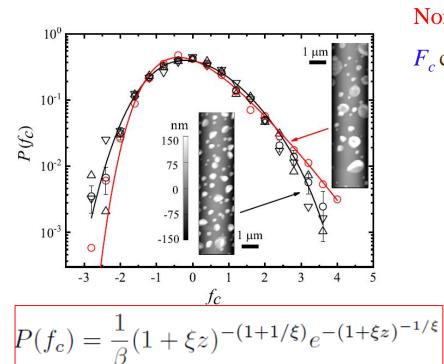


Fig. 3. *Ra* dependence of the PDF of the massive eruption events. (A to C) Measured PDF $P(\zeta')$ (open symbols) as a function of the normalized variable $\zeta' = \zeta/\sigma_{\zeta}$ with different values of *Ra* for (A) water (*Pr* = 4.4), (B) 10% glycerin solution (*Pr* = 5.7), and (C) 20% glycerin solution (*Pr* = 7.6). The solid lines show the fits of the GEV distribution in Eq. 3 to the data points with (A) $\chi = -0.001$, (B) $\chi = -0.04$, and (C) $\chi = -0.07$, respectively. Y. Wang et. al., Sci. Adv. 4: eaat7480 (2018)

Extreme Value Statistics in moving contact line: contact line deforms and eventually depinning occurs

- contact line deforms to accumulate stronger force to de-pin
- A large number of pinning sites along the contact line loop
- Fc ~ maximum of the pinning forces
- As the contact line is pulled: sample the maximum of the (~independent pinning forces) on the contact line → GEV



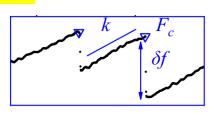
Normalized depinning force
$$f_c = \frac{F_c - \langle F_c \rangle}{\sigma_{F_c}}$$

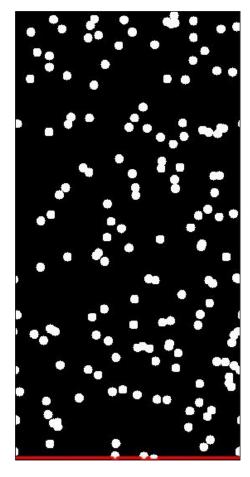
$$F_c$$
 contains an eqm. force $F_{eq} = -\pi d\gamma \cos \theta$

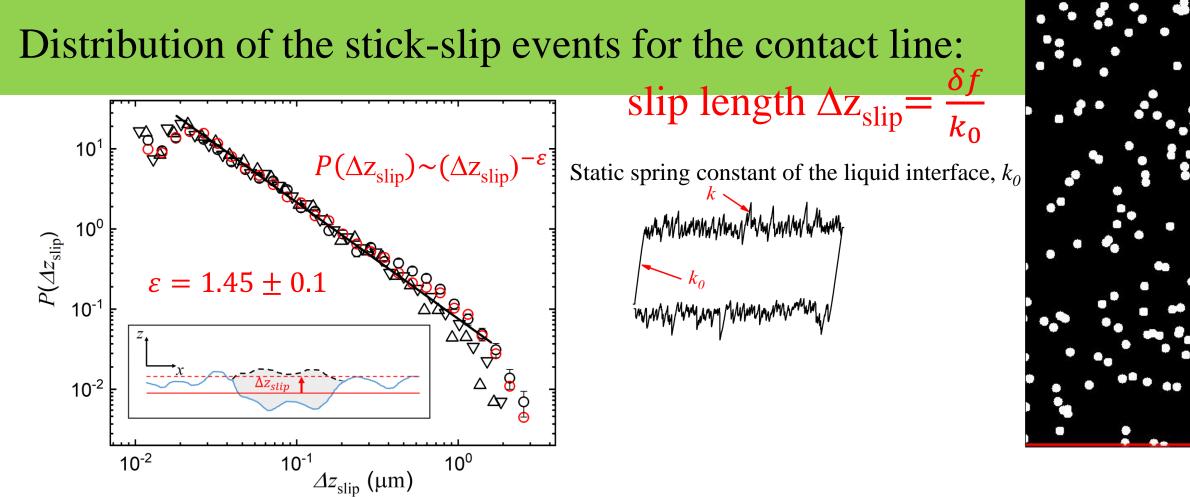
 $\xi = -0.17$ (black line) $\xi = -0.06$ (red line)

 $\xi < 0$ reversed Weibull distribution: has an upper bound $(f_c)_M = \mu - \beta/\xi$ beyond which $P(f_c) = 0 \rightarrow$ an upper bound for $(F_c)_M$. Roughness-induced maximal pinning force = $(F_c)_M - F_{eq}$, larger for the rougher surface(750 vs. 402 nN)

 $\xi = 0$ Gumbel distribution: exponential tail with an infinite upper bound $[(f_c)_M \rightarrow \infty]$.

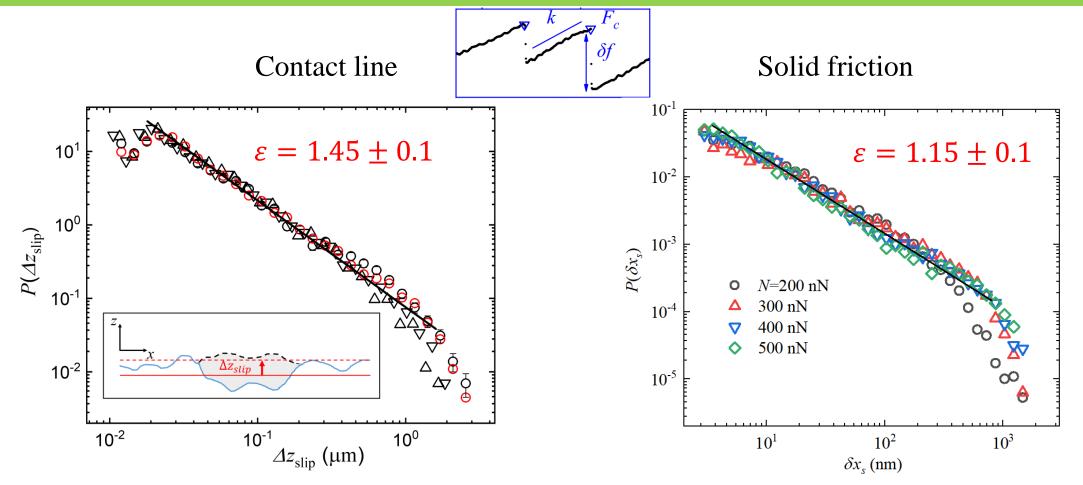






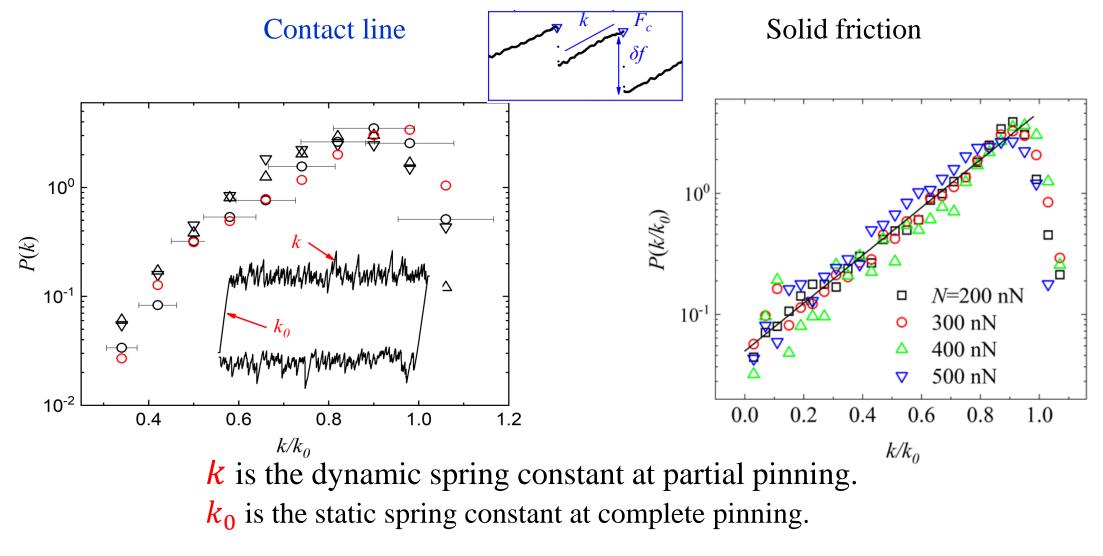
- Power-law distribution is hallmark of the avalanche dynamics.
- when a strong defect slips, the released large stress is partially transferred to its neighboring defects and triggers their slips→ avalanche
- ϵ is unchanged for fibers with different roughnesses and in contact with different liquids
- In the low-speed limit, the Alessandro-Beatrice-Bertotti-Montorsi(ABBM) model predicts $\epsilon = 3/2 \rightarrow$ slow CL motion obeys the ABBM model

Distribution of the stick-slip events: Slip length = $\frac{\delta f}{k_0}$



- Power-law distribution is hallmark of the avalanche dynamics.
- The power-law exponent $\varepsilon \sim 1.5$ (ABBM) of the CL is larger than that of the solid friction: $\varepsilon \sim 1.2$ (quasi-1D), $\varepsilon \sim 0.72$ (2D probe).

Distribution of the stick-slip events: Dynamic spring constant k



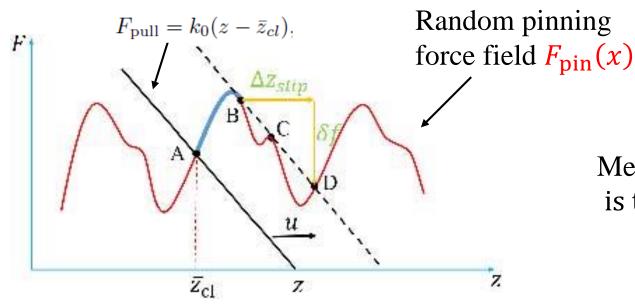
 $0.3 \lesssim k/k_{\scriptscriptstyle 0} \lesssim 1.1$ and peaks around $k/k_{\scriptscriptstyle 0} \simeq 0.94$

\rightarrow k₀ sets a cutoff value for k

Theoretical model: Stick-slip motion in a random pinning field

h(x; z): defect-induced heterogeneous interfacial tension difference between the solid-air and solid-liquid interfaces

Elastic pulling force



Dynamic balance between F_{pull} and F_{pin}

 $F_{\text{pin}} = \int_{0}^{\pi a} h(x; z_{cl}(x)) dx.$ Indom pinning
Icce field $F_{\text{pin}}(x)$ Ic

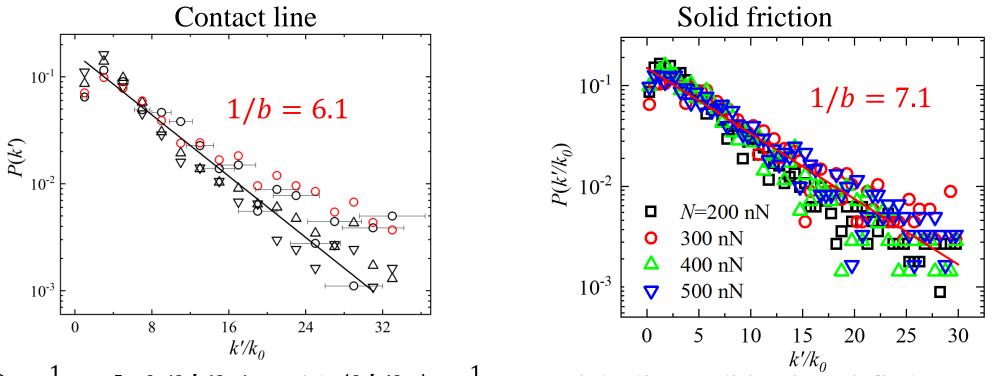
Downhill $(B \rightarrow C)$:

Slip instability occurs when $k_0 < k'$. Slip length $\Delta z_{slip} = \frac{\delta f}{k_0}$.

Microscopically:
$$\delta f = -\langle \partial h / \partial z \rangle_A \int_A dx dz = \frac{k_0}{\pi d} \int_A dx dz = k_0 \Delta z_{slip}$$

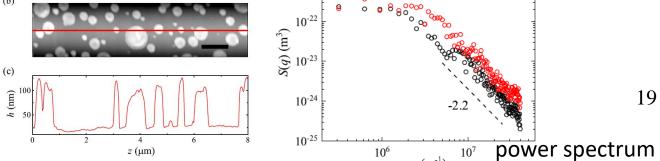
the slip area 18

Distribution of the stick-slip events: local pinning force gradient k'



• $P(k') = \frac{1}{b} \exp[-b(k'/k_0)]$, with $\langle k'/k_0 \rangle = \frac{1}{b} \gg 1$ (stick-slip condition is satisfied).

- Exponential distribution of k' is common in dynamically or spatially heterogeneous systems
- Broad surface height roughness distribution:^(b)



Damped spring-block model for stick-slip dynamics

Governing equation of the stick-slip motion (center-of-mass of scanning probe x_s):

$$m\frac{d^2x_s}{dt^2} = -\gamma\frac{dx_s}{dt} + k(u_0t - x_s) - F_{\text{pin}}(x_s)$$

Brownian-correlated pinning force: $\langle |F_{\text{pin}}(x_s) - F_{\text{pin}}(x'_s)|^2 \rangle = 2D|x_s - x'_s|$

Cantilever

Sandpaper

Laser

Scan direction

• an extension of the Prandtl and Tomlinson model (widely used in the study of atomic stick-slip friction), in which $F_{pin}(x_s)$ was assumed to be of a sinusoidal form for atomic friction over a single crystalline surface.

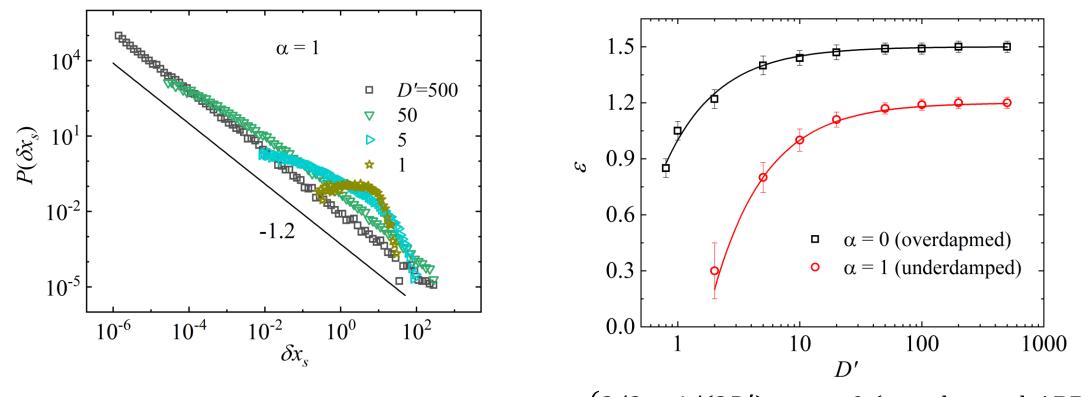
$$U = \frac{dx_s}{dt} / u_0 \Rightarrow \text{Langevin-type equation with multiplicative noise:}$$
$$\alpha \frac{d^2 U}{dT^2} = -\frac{dU}{dT} + 1 - U + \sqrt{U}\xi(T); \quad \langle \xi(T) \rangle = 0, \langle \xi(T)\xi(T') \rangle = 2D'\delta(T - T')$$

 $\alpha = mk/\gamma^2 \begin{cases} = 0, & \text{overdamped, ABBM} \\ \ge 1/4, & \text{underdamped} \end{cases}$ $D' = D/k\gamma u_0 \begin{cases} \gg 1, & \text{strong pinning} \\ \le 1, & \text{weak pinning} \end{cases}$

Numerical solution: $U(T = 0) = 0; U(T = T_s) = 0$ Slip length: $\delta x_s \equiv \int_0^{T_s} U(T) dT$

Damped spring-block model for stick-slip dynamics in solid friction

Numerical results



 $\epsilon = \begin{cases} 3/2 - 1/(2D'), & \alpha = 0 \text{ (overdamped, ABBM)} \\ 1.2 - 2/D', & \alpha \ge 1/4 \text{ (underdamped)} \end{cases}$

Distribution of the slip length: $P(\delta x_s) \sim \delta x_s^{-\varepsilon}$

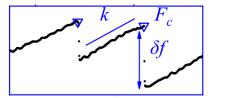
Conclusions

- Stick-slip friction and contact line pinning-depinning at mesoscale (at the single slip resolution) obey the statistical laws that are often associated with the avalanche dynamics at a critical state.
- seemingly chaotic stick-slip friction at mesoscale obeys precise statistical laws
- The avalanche (stick-slip) dynamics of a contact line or solid are governed by three statistical laws:
 - 1) GEV distribution for the depinning force;
 - 2) Power-law distribution of the slip length;
 - 3) Exponential distribution of the local pinning force gradient k'
- The power-law exponent ε for the avalanche size can be caused by the magnitude of damping, with $\varepsilon = 1.5$ for the overdamped contact line and $\varepsilon \sim 1.2$ for the (quasi 1D)underdamped solid friction.
- The proposed damped spring-block model under a Brownian-correlated pinning force field captures the essential physics of the stick-slip friction at mesoscale

Collaborators:

Penger Tong (HKUST), Hsuan-Yi Chen (National Central University, Taiwan)

- Dr. Caishan Yan (HKUST), Dr. Dongshi Guan, Dr. Yin Wang
- "Statistical laws of stick-slip friction at mesoscale", Nature Comm. **14**:6221 (2023).
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 $P(\delta x_s) \sim (\delta x_s)^{-\varepsilon}$

 $\delta f = k_0 \delta x_s$